

**A METHOD OF TESTING A SEQUENTIAL ACCESS MEMORY
PLANE AND A CORRESPONDING SEQUENTIAL ACCESS
MEMORY SEMICONDUCTOR DEVICE**

ABSTRACT

The sequential access memory array is able to store p words each of n bits. Such p test words each made up of n test bits are written in the memory array, the p test words are extracted sequentially and, for
5 each current word extracted, the n test bits that compose it are compared sequentially with n respective expected data bits before extracting the next test word.

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